Search Notes

Application/Control No.	Applicant(s)/Patent un Reexamination	der
10/681,544	NG ET AL.	
Examiner	Art Unit	
Ernest F. Karlsen	2829	

Ernest F. Karlsen

SEARCHED				
Class	Subclass	Date	Examiner	
324	751 765	4/20/2005	E.7.K.	
714	736 737	4/20/2005	E.7K	
		*****		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
324	751 765	4/20/2005	87.8	
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			1	

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY	)
	DATE	EXMR
voltage adj contrast and electron adj beam library same cell same test same semiconductor	4/20/2005	E.A.